



# Enabling MLC Flash SSD In Enterprise Storage

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## Agenda

- Enterprise MLC SSD Enablement: Current Trend
- MLC NAND Scaling Trend & Outlook
- Enterprise Support Challenges: MLC SSD Controllers
- Enterprise Support Challenges: MLC Flash Media
- Dwell Time: Key Lever for SSD Reliability Improvement
- SSD Small Factor Innovation Required for Enterprise
- Summary

## MLC SSD Enablement: Current Trend

- MLC Flash component endurance support has been extended to between consumer MLC and SLC for a given technology
  - Achieved via early signal processing implementation or program time degradation
- Power off data retention now optimized for Enterprise SSD
  - Duration requirement reduced from traditional 1-year to 3-months
    - Aligned with Enterprise field maintenance strategies
    - Further optimization may be required as technology advances
  - Temperature support reduced from 55°C to 40°C
    - Consistent with most data center environments
- ECC support per sector enhanced by industry SSD controllers
  - Required to satisfy 3x/2xnm MLC targets
  - Continuing improvements required in architecture / support level
- **NET: *MLC Flash provides leadership Enterprise SSD performance and lifespan today based on existing storage infrastructure***
  - Higher capacity and lower cost structure enabled

## MLC NAND Scaling Trend & Outlook

	2009	2010	2011	2012	2013	2014	2015
Technology (nm)	3x	2x	2y	2y/1x	1x	1x	1y
Cell Architecture	Floating Gate	Floating Gate	Floating Gate	Floating Gate	Floating Gate	Charge Trap Device / 3D	Charge Trap Device / 3D
Bit Line Architecture	Shared Bit Line / All Bit Line	Shared Bit Line / All Bit Line	All Bit Line	All Bit Line	All Bit Line	<New Sensing Scheme>	<New Sensing Scheme>
MLC Density (Gb)	32	64	64	128	128	256	256

- Floating gate NAND cell scaling likely to continue to 1xnm technology node range in ~ 2013, based on conventional immersion lithography
- NAND scaling expected to continue beyond 2013 @ lower 1x nm NAND nodes, based on charge trap device and 3-D NAND cell & process architecture, reaching MLC NAND densities of 256Gb & higher
- NAND scaling rate and pace is based on consumer and not enterprise reliability requirements
- Ongoing enhancements (e.g., signal processing) required to achieve Enterprise-level MLC reliability requirements vs. time

**NET: NAND scaling expected to continue via floating gate extension & charge trap / 3D cell architectures to 1xnm technology node range and 256Gb MLC density**

- **Ongoing reliability enhancements required to satisfy Enterprise-level MLC requirements vs. time**

## Enterprise Support Challenges: MLC SSD Controllers

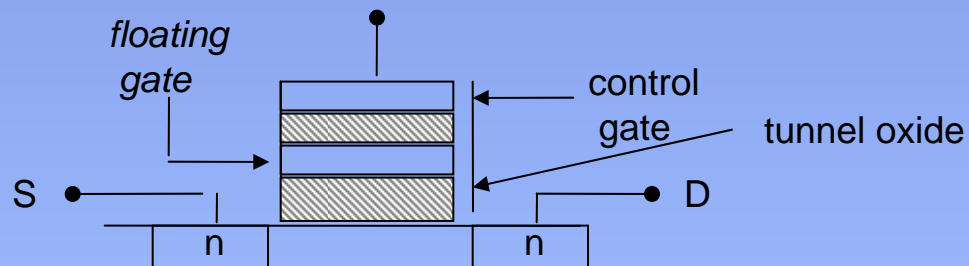
Controller Feature	Description
Advanced wear leveling	<ul style="list-style-type: none"> <li>Continuing innovation to spread Flash usage as evenly as possible to help maximize SSD life</li> </ul>
Flash usage management	<ul style="list-style-type: none"> <li>Implementation of various potential techniques such as compression, de-duplication, etc. to help limit Flash wear</li> </ul>
Forward-looking ECC architecture / coverage	<ul style="list-style-type: none"> <li>Advanced architecture capability</li> <li>Multiple Flash technology node support</li> </ul>
Write amplification optimization	<ul style="list-style-type: none"> <li>Provide maximum media lifespan capability</li> </ul>
Advanced signal processing support	<ul style="list-style-type: none"> <li>Flash component partnership likely required</li> <li>Key next-generation Flash reliability improvement mechanism</li> </ul>
System-level throttling capability	<ul style="list-style-type: none"> <li>Innovative methods to help manage Flash bandwidth to achieve improved SSD lifespan</li> </ul>
Response time improvement	<ul style="list-style-type: none"> <li>Drive average and maximum response time improvements with increased SSD complexity</li> </ul>
Trim command support / utilization	<ul style="list-style-type: none"> <li>Vehicle for improving mature SSD performance / lifespan</li> </ul>
Power consumption reduction	<ul style="list-style-type: none"> <li>Manage power with increased performance</li> <li>Subsystem-level RAID level power will increase with Flash optimization</li> </ul>
End-to-end data integrity support	<ul style="list-style-type: none"> <li>Fundamental requirement for Enterprise SSD</li> </ul>

## Enterprise Support Challenges: MLC NAND Flash Media

- Providing Enterprise support while driving aggressive technology advancement / cost reduction for Consumer applications with reduced reliability requirements is critical Flash industry challenge
- MLC NAND technology lifespan must be extended to support Enterprise product requirements
- New MLC component designs must offer additional spare area per sector to accommodate advanced ECC algorithms required for Enterprise
- Next key technology transition is advanced signal processing access capability provided by MLC suppliers to SSD controller designers / manufacturers
- Component read disturb specifications must be better understood by controller companies / users
  - JEDEC read disturb specification needed
- Drive-to goal for Enterprise Flash storage must be ***to apply consumer MLC to enterprise SSD applications with sufficient controller Flash management and reliability***

## Dwell Time: Key Lever For SSD Reliability Improvement

- Definition
  - Dwell time – elapsed time between program operations for individual Flash component cells
    - Typically 2-10 min. for current industry component qualifications based on density and endurance targets – result based on qualification goals not Enterprise system requirements
- Concept
  - Increased dwell time allows for improved Flash cell recovery (de-trapping)
  - Initial test data shows increased dwell time improves retention UBER and RBER at both 25°C and 85°C
    - Data on different suppliers and various technology nodes
  - NET: Flash component endurance can be increased at constant data retention with extended dwell time
- SSD / system applications
  - Flash component dwell time is on average significantly longer in system environment behind host and SSD controllers with Flash management architectures
  - System- and storage subsystem-level characterization in process
- Recommendation
  - **Drive Flash component dwell time specification for Enterprise SSD based on available component-, SSD- and system-level data**
    - Significant reliability improvement opportunity exists



## Small Form Factor Innovation Required for Enterprise

### ▪ SSD

- **1.8" Enterprise SFF SSD** enables high capacity and throughput per system space allocated
  - MLC Flash media is key to value proposition
  - Enterprise data integrity requirements must be satisfied
  - SATA interface now, migrate to SAS by YE11
  - Industry defined Micro SAS connector SFF (8486)
  - Connector power requirements must be defined for 6 and 12Gbps interface speeds, enabling maximum SSD performance
  - Application opportunities
    - Boot drives for systems requiring small footprint and minimum space (e.g., blades )
    - Low-end rack servers
    - PCI-e adapter card building block
- High performance **one-chip SSD controller** solutions without dependence on external caches required
- New approaches needed for **super capacitor** designs (if required) to help improve reliability and reduce space occupancy
  - Discrete capacitors
  - Other backup mechanisms (e.g., phase change memory)



## Small Form Factor Innovation Required for Enterprise

- **NAND Flash Media**
  - **12mm x 18mm BGA** body size support must be drive-to goal with advanced technology and increased density
    - Enables increased number of controller channels / Flash sites
  - Packaging innovation required to support **greater than 8 dice per Flash package** for increased capacity with similar reliability

## Summary

- MLC Flash currently provides leadership Enterprise SSD performance and lifespan today based on existing storage infrastructure
  - Higher capacity and lower cost structure enabled
- NAND scaling expected to continue via floating gate extensions & charge trap / 3D cell architectures to 1xnm technology node range and 256Gb MLC density
  - Ongoing reliability enhancements required to satisfy Enterprise-level MLC requirements vs. time
- Enterprise SSD controller and Flash media challenges must be overcome to ensure MLC support through time
- Flash component dwell time is likely new lever for Enterprise SSD reliability improvement
- Small form factor innovation is required for Enterprise storage to enable improved capacity, performance and reliability